

Notice of References Cited	Application/Control No. 10/714,617		Applicant(s)/Patent Under Reexamination CHIU ET AL.	
	Examiner ERIC YEN		Art Unit 2626	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-7,103,316	09-2006	Hall, Steven Deane	455/63.1
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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